

<b>Notice of References Cited</b>	Application/Control No. 09/821,029	Applicant(s)/Patent Under Reexamination TOKUMARU ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,809,415	09-1998	Rossmann, Alain	455/422.1
	B	US-6,473,609	10-2002	Schwartz et al.	455/406
	C	US-6,647,260	11-2003	Dusse et al.	709/219
	D	US-6,606,663	08-2003	Liao et al.	709/229
	E	US-6,597,903	07-2003	Dahm et al.	455/405
	F	US-2002/0160790	10-2002	Schwartz et al.	455/456
	G	US-2002/0068554	06-2002	DUSSE, STEVE	709/219
	H	US-2002/0015480	02-2002	Daswani et al.	379/88.17
	I	US-2001/0037490	11-2001	Chiang, Hiang-Swee	717/2
	J	US-5,001,729	03-1991	Tjahjadi et al.	375/355
	K	US-6,684,257	01-2004	Camut et al.	709/246
	L	US-5,727,159	03-1998	Kikinis, Dan	709/246
	M	US-6,076,166	06-2000	Moshfeghi et al.	713/201

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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